

100W 10dB DC-3GHz BeO Flanged Attenuator

A1000-100-11X

A1000-100-11X Features:

- Flange Mount
- RoHS Compliant
- Customer Defined Testing Available
- · High Rated Power
- Covered Resistive Element
- Symmetrical Design¹



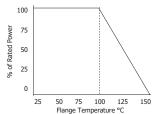
A1000-100-11X Parameters:

Nominal Attenuation: 10dB
Operating Frequency: DC - 3GHz
Attenuation Tolerance: ± 0.5 dB
Return Loss (Typical)*: 20dB or Better
Input Power: ± 0.0 0W**
Impedance: ± 0.0 0

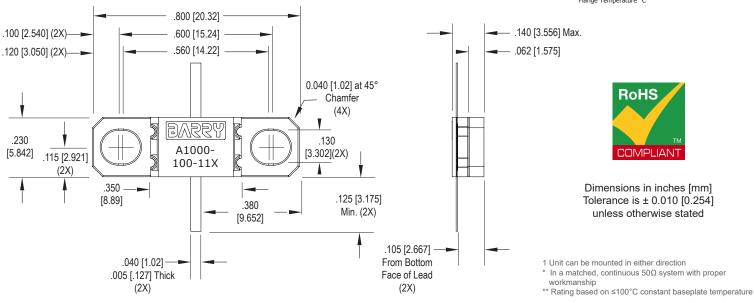
Resistor Construction: Thick Film on BeO
Flange Construction: Silver Plated Copper
Lead Construction: Silver Plated Copper

Operating Temperature: -55 to +150°C

A1000-100-11X Power Derating Curve



A1000-100-11X Dimensions:



Ordering Information:



Barry Industries reserves the right to change part number and/or process without notification.



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A1000-100-11X Reliability Data:

Parameter:	Test Condition:	Results:
Short Time Overload	Apply 1.1x Rated Power for 5 Seconds.	≤ 5.0% Resistance Shift
Rated Load Life	Apply 1/2 Power Under 40°C ±2°C 90 Minutes on/ 30 Minutes off. Repeat for 100 hours	≤ 5.0% Resistance Shift
Moisture Resistance	MIL-PRF-55342 para.4.8.9 95% RH, 25°C - 65°C	≤ 5.0% Resistance Shift
Resistance to Soldering Heat (Lead)	MIL-STD-202 Method 210 Test Condition "A"	≤ 5.0% Resistance Shift
Resistance to Soldering Heat (Assembly)	MIL-STD-202 Method 210 Test Condition "J"	≤ 5.0% Resistance Shift
Terminal Strength	MIL-STD-202 Method 211 Test Condition "A" 3lbs. Test Condition "B" 5 bends	No Significant Abnormality (Visual)
Solderability (Lead only)	MIL-STD-202 Method 208 Test C	>95% Covered
High Temperature Storage	125°C ±2°C for 500 Hours	1.) ≤ 5.0% Resistance Shift2.) No Significant Abnormality (Visual)
Thermal Shock	-5°C to +150°C 30 Minutes Dwell, 5 Cycles	1.) ≤ 5.0% Resistance Shift2.) No Significant Abnormality (Visual)

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